## Notice of References Cited Application/Control No. 10/773,629 Examiner JOHN J. LEE Applicant(s)/Patent Under Reexamination KRISHNAN ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,647,273	11-2003	Parssinen et al.	455/522
*	В	US-6,697,634	02-2004	Hayashi, Masaki	455/522
*	С	US-6,788,138	09-2004	Suzuki, Hiroshi	330/129
*	D	US-2004/0062216	04-2004	Nicholls et al.	370/320
	Ε	US-			
	F	US-			
	G	US-			
	Н	US-			
	ı	US-			
	J	US-			
	K	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	S					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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